

transitions, transition temperatures, and domain size and order, of transition metal oxides, especially magnetoelectric multiferroics, manganites, vanadates, and superconductors. *Justification for Duty-Free Entry:* No instruments of the same general category, or comparable instruments that could otherwise be used for the intended purpose, are being manufactured in the United States. *Application accepted by Commissioner of Customs:* June 28, 2011.

*Docket Number:* 11–041. *Applicant:* Washington University, 660 South Euclid Avenue, Saint

Louis, MO 63110–1093. *Instrument:* Transmission electron microscope. *Manufacturer:* JEOL Ltd., Japan. *Intended Use:* The instrument will be used to provide dependable ultrastructural analysis to NIH-sponsored investigators, extending their capacity to ask disease-related and basic science questions with a more sophisticated approach to analyzing the relationship of subcellular elements. *Justification for Duty-Free Entry:* No instruments of the same general category, or comparable instruments that could otherwise be used for the intended purpose, are being manufactured in the United States. *Application accepted by Commissioner of Customs:* June 30, 2011.

Dated: July 12, 2011.

**Gregory W. Campbell,**  
*Director, Subsidies Enforcement Office, Office of Policy, Import Administration.*

[FR Doc. 2011–18298 Filed 7–19–11; 8:45 am]

**BILLING CODE 3510–DS–P**

## DEPARTMENT OF COMMERCE

### International Trade Administration

#### Wichita State University, et al.; Notice of Decision on Applications for Duty-Free Entry of Scientific Instruments

This is a decision pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, as amended by Pub. L. 106–36; 80 Stat. 897; 15 CFR Part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Room 3720, U.S. Department of Commerce, 14th and Constitution Ave., NW., Washington, DC 20230.

*Comments:* None received. *Decision:* Approved. *Reasons:* We know of no instruments of equivalent scientific value to the foreign instruments described below, for the intended purposes, that were being manufactured in the United States at the time of their order.

*Docket Number:* 11–013. *Applicant:* Wichita State University, 1845 Fairmont Street, Wichita, KS 67260. *Instrument:* Field emission scanning electron microscope. *Manufacturer:* Carl Zeiss SMT, Germany. *Intended Use:* See application notice at 76 FR 34207, June 13, 2011.

*Docket Number:* 11–029. *Applicant:* University of California, Santa Barbara, CA 93106. *Instrument:* Josephson Junction Deposition System (Electron Beam Evaporation Unit with Load Lock Model MEB 550S). *Manufacturer:* Plassys Bestek SAS, France. *Intended Use:* See application notice at 76 FR 34207, June 13, 2011.

Dated: July 12, 2011.

**Gregory W. Campbell,**  
*Director, Subsidies Enforcement Office, Office of Policy, Import Administration.*

[FR Doc. 2011–18296 Filed 7–19–11; 8:45 am]

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## DEPARTMENT OF COMMERCE

### International Trade Administration

#### University of Chicago Argonne, LLC, et al.; Notice of Decision on Applications for Duty-Free Entry of Scientific Instruments

This is a decision pursuant to Section 6(c) of the Educational, Scientific, and Cultural Materials Importation Act of 1966 (Pub. L. 89–651, as amended by Pub. L. 106–36; 80 Stat. 897; 15 CFR Part 301). Related records can be viewed between 8:30 a.m. and 5 p.m. in Room 3720, U.S. Department of Commerce, 14th and Constitution Ave., NW., Washington, DC 20230.

*Docket Number:* 10–073. *Applicant:* University of Chicago Argonne, LLC, 9700 South Cass Avenue, Argonne, IL 60439. *Instrument:* Chemical Mechanical Polishing (CMP) Tool. *Manufacturer:* Logitech Ltd., UK. *Intended Use:* See application notice at 76 FR 34207, June 13, 2011. *Comments:* None received. *Decision:* Approved. *Reasons:* We know of no instrument of equivalent scientific value to the foreign instrument described above, for such purposes as this is intended to be used, that was being manufactured in the United States at the time of its order.

Dated: July 12, 2011.

**Gregory W. Campbell,**  
*Director, Subsidies Enforcement Office Office of Policy, Import Administration.*

[FR Doc. 2011–18295 Filed 7–19–11; 8:45 am]

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## DEPARTMENT OF COMMERCE

### National Institute of Standards and Technology

#### Proposed Information Collection; Comment Request; NIST MEP Client Impact Survey

**AGENCY:** National Institute of Standards and Technology (NIST), Commerce.  
**ACTION:** Notice.

**SUMMARY:** The Department of Commerce, as part of its continuing effort to reduce paperwork and respondent burden, invites the general public and other Federal agencies to take this opportunity to comment on proposed and/or continuing information collections, as required by the Paperwork Reduction Act of 1995.

**DATES:** Written comments must be submitted on or before September 19, 2011.

**ADDRESSES:** Direct all written comments to Diana Hynek, Departmental Paperwork Clearance Officer, Department of Commerce, Room 6616, 14th and Constitution Avenue, NW., Washington, DC 20230 (or via the Internet at [dHynek@doc.gov](mailto:dHynek@doc.gov)).

**FOR FURTHER INFORMATION CONTACT:** Requests for additional information or copies of the information collection instrument and instructions should be directed to Christopher Carbone, (301) 975–2952, [ccarbone@nist.gov](mailto:ccarbone@nist.gov).

#### SUPPLEMENTARY INFORMATION:

##### I. Abstract

Sponsored by the National Institute of Standards and Technology (NIST), the Manufacturing Extension Partnership (MEP) is a national network of locally-based manufacturing extension centers working with small manufacturers to assist them to improve their productivity, profitability, and enhance their economic competitiveness. The information collected will provide the MEP with information regarding MEP Center performance in the delivery of technology, and business solutions to U.S.-based manufacturers. The collected information will assist in determining the performance of the MEP Centers at both local and national levels, provide information critical to monitoring and reporting on MEP programmatic performance, and assist management in policy decisions. Responses to the collection of information are mandatory per the regulations governing the operation of the MEP Program (15 CFR Parts 290, 291, 292, and H.R. 1274—section 2). The information collected will include MEP customer inputs regarding their sales, costs, investments,